

<b>Notice of References Cited</b>	Application/Control No. 10/518,948		Applicant(s)/Patent Under Reexamination DOU ET AL.	
	Examiner Mark Kopec		Art Unit 1796	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dou et al "Transport Critical Current Density in Fe-Sheathed Nano-SiC Doped MgB <sub>2</sub> Wires", IEEE Transactions on Applied Superconductivity, Vol 13, No 2, June 2003 (3199-3202).
	V	
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